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MEASUREMENT REPORT FCC Part 15.225 / IC RSS-210 NFC

Applicant Name:

Samsung Electronics, Co. Ltd.
416 Maetan 3-Dong, Yeongtong-gu
Suwon-si, Gyeonggi-do
443-742, Republic of Korea

Date of Testing:

April 20, 2012

Test Site/Location:

PCTEST Lab, Columbia, MD, USA

Test Report Serial No.:

0Y1204030418.A3L

FCC ID:

A3LSHVE170S

APPLICANT:

Samsung Electronics, Co. Ltd.

Application Type:

Certification

Model(s):

SHV-E170S

EUT Type:

Portable Handset

Frequency:

13.56MHz

FCC Classification:

Low Power Communications Device Transmitter (DXX)

FCC Rule Part(s):

FCC Part 15 Subpart C (15.225)

IC Specification(s):

RSS-210 Issue 8

Test Procedure(s):

ANSI C63.4-2003/2009

The device bearing the FCC Identifier specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and has been tested in accordance with the measurement procedures specified in ANSI C63.4-2003/2009 (See Test Report). These measurements were performed with no deviation from the standards. Test results reported herein relate only to the item(s) tested.

I authorize and attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

NVLAP accreditation does not constitute any product endorsement by NVLAP or any agency of the United States Government. This report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government. PCTEST certifies that no party to this application has been subject to a denial of Federal benefits that includes FCC benefits pursuant to Section 5301 of the Anti-Drug Abuse Act of 1988, 21 U.S.C. 862.


Randy Ortanez
President


Lab Code 100431-0

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 1 of 21

T A B L E O F C O N T E N T S

FCC Part 15.225 MEASUREMENT REPORT	3
1.0 INTRODUCTION	4
1.1 SCOPE	4
1.2 PCTEST TEST LOCATION	4
2.0 PRODUCT INFORMATION	5
2.1 EQUIPMENT DESCRIPTION	5
2.2 DEVICE CAPABILITIES	5
2.3 TEST CONFIGURATION	5
2.4 EMI SUPPRESSION DEVICE(S)/MODIFICATIONS	5
2.5 LABELING REQUIREMENTS	5
3.0 DESCRIPTION OF TEST	6
3.1 EVALUATION PROCEDURE	6
3.2 AC LINE CONDUCTED EMISSIONS	6
3.3 RADIATED EMISSIONS	7
4.0 ANTENNA REQUIREMENTS	8
5.0 SAMPLE CALCULATIONS	9
5.1 CONDUCTED EMISSION MEASUREMENT SAMPLE CALCULATION	9
5.2 RADIATED EMISSION MEASUREMENT SAMPLE CALCULATION	9
6.0 TEST EQUIPMENT CALIBRATION DATA	10
7.0 ENVIRONMENTAL CONDITIONS	11
8.0 TEST DATA	12
8.1 SUMMARY	12
8.2 20DB BANDWIDTH MEASUREMENT	13
8.3 FREQUENCY STABILITY TEST DATA	14
8.4 IN-BAND RADIATED SPURIOUS EMISSION MEASUREMENTS	16
8.5 RADIATED SPURIOUS EMISSION MEASUREMENTS, OUT-OF-BAND	17
8.6 LINE CONDUCTED MEASUREMENT DATA	19
9.0 CONCLUSION	21

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 2 of 21



MEASUREMENT REPORT

FCC Part 15.225



§ 2.1033 General Information

APPLICANT: Samsung Electronics, Co. Ltd.
APPLICANT ADDRESS: 416 Maetan 3-Dong, Yeongtong-gu
 Suwon-si, Gyeonggi-do
 443-742, Republic of Korea
TEST SITE: PCTEST ENGINEERING LABORATORY, INC.
TEST SITE ADDRESS: 7185 Oakland Mills Road, Columbia, MD 21046 USA
FCC RULE PART(S): Part 15 Subpart C (15.225)
IC SPECIFICATION(S): RSS-210 Issue 8
MODEL: SHV-E170S
FCC ID: A3LSHVE170S
Test Device Serial No.: FJ-053-A ☐ Production ☒ Pre-Production ☐ Engineering
FCC CLASSIFICATION: Low Power Communications Device Transmitter (DXX)
DATE(S) OF TEST: April 20, 2012
TEST REPORT S/N: 0Y1204030418.A3L

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.



- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules.
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 3 of 21

1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 PCTEST Test Location

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Intern't'l (BWI) airport, the city of Baltimore and the Washington, DC area. (See Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003/2009 on February 15, 2012.

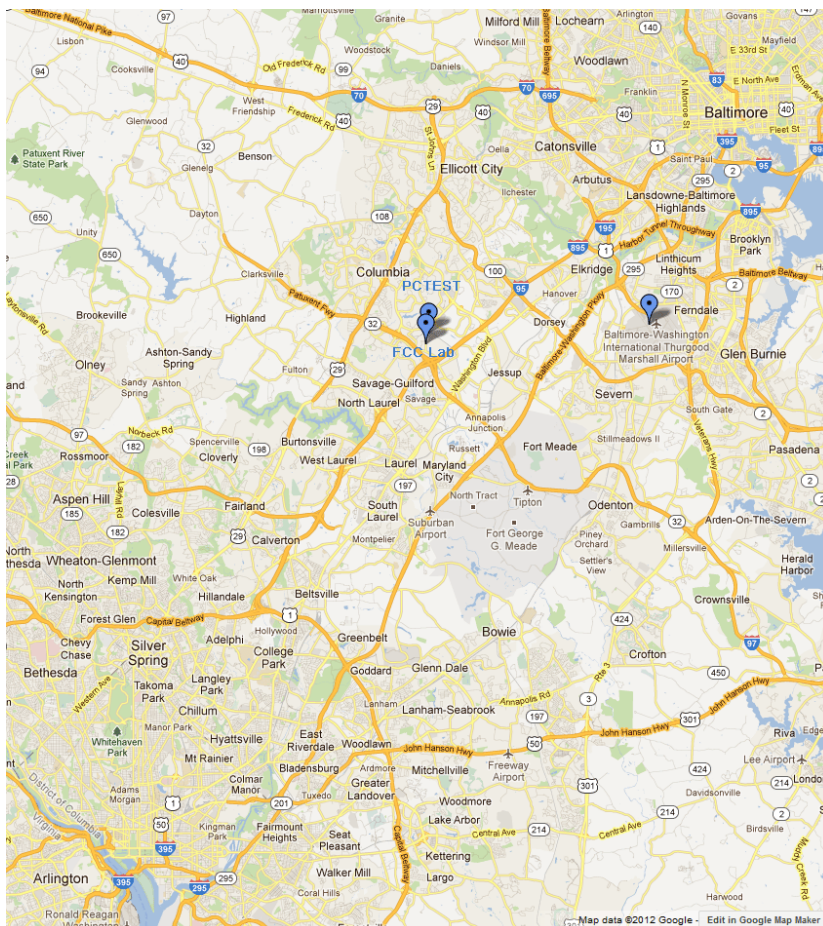


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 4 of 21

2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSHVE170S**. The test data contained in this report pertains only to the emissions due to the NFC transmitter of the EUT.

2.2 Device Capabilities

This device contains the following capabilities:

1900 GSM/GPRS, 1900 WCDMA/HSPA, 802.11a/b/g/n WLAN, 802.11a/n UNII, Bluetooth (1x,EDR), NFC

2.3 Test Configuration

The Samsung Model: SHV-E170S, FCC ID: A3LSHVE170S was set to continuously transmit at 13.56MHz. This was performed using manufacturer software loaded on the phone to allow for continuous transmission. This device was tested in accordance with the guidance of ANSI C63.4-2003/2009. See Sections 3.2 and 3.3 of this test report for a description of the AC line conducted emissions and radiated emissions test setups, respectively.

2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.5 Labeling Requirements

Per 15.19; Docket 95-19

The label shall be permanently affixed at a conspicuous location on the device; instruction manual or pamphlet supplied to the user and be readily visible to the purchaser at the time of purchase. However, when the device is so small wherein placement of the label with specified statement is not practical, only the trade name and FCC ID must be displayed on the device per Section 15.19(b)(2).

Please see attachment for FCC ID label and label location.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 5 of 21

3.0 DESCRIPTION OF TEST

3.1 Evaluation Procedure

The measurement procedure described in the American National Standard for Methods of Measurement of Radio-Noise Emission from Low-Voltage Electrical and Electronic Equipment in the Range of 9kHz to 40GHz (ANSI C63.4-2003/2009) was used in the measurement of the **Samsung Portable Handset FCC ID: A3LSHVE170S**.

Deviation from measurement procedure.....None

3.2 AC Line Conducted Emissions

The line-conducted facility is located inside a 10'x16'x9' shielded enclosure. The shielded enclosure is manufactured by ETS Lindgren RF Enclosures. The shielding effectiveness of the shielded room is in accordance with MIL-Std-285 or NSA 65-5. A 1m x 1.5m wooden table 80cm high is placed 40cm away from the vertical wall and 80cm away from the sidewall of the shielded room. Two 10kHz-30MHz, 50Ω/50μH Line-Impedance Stabilization Networks (LISNs) are bonded to the shielded room floor. Power to the LISNs is filtered by external high-current high-insertion loss power line filters. The external power line filter is an ETS Lindgren Model LPRX-4X30 (100dB Attenuation, 14kHz-18GHz) and the two EMI/RFI filters are ETS Lindgren Model LRW-2030-S1 (100dB Minimum Insertion Loss, 14kHz – 10GHz). These filters attenuate ambient signal noise from entering the measurement lines. These filters are also bonded to the shielded enclosure.

The EUT is powered from one LISN and the support equipment is powered from the second LISN. If the EUT is a DC-powered device, power will be derived from the source power supply it normally will be powered from and this supply line(s) will be connected to the second LISN. All interconnecting cables more than 1 meter were shortened to a 1 meter length by non-inductive bundling (serpentine fashion) and draped over the back edge of the test table. All cables were at least 40cm above the horizontal reference groundplane. Power cables for support equipment were routed down to the second LISN while ensuring that that cables were not draped over the second LISN.

Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The RF output of the LISN was connected to the spectrum analyzer and exploratory measurements were made to determine the frequencies producing the maximum emission from the EUT. The spectrum was scanned from 150kHz to 30MHz with a spectrum analyzer. The detector function was set to peak mode for exploratory measurements while the bandwidth of the analyzer was set to 10kHz. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each emission. Each emission was also maximized by varying: power lines, the mode of operation or resolution, clock or data exchange speed, scrolling H pattern to the EUT and/or support equipment whichever determined the worst-case emission. Once the worst case emissions have been identified, the one EUT cable configuration/arrangement and mode of operation that produced these emissions is used for final measurements on the same test site. The analyzer is set to CISPR quasi-peak and average detectors with a 9kHz resolution bandwidth for final measurements.

Line conducted emissions test results are shown in Section 8.6. Automated test software was used to perform the AC line conducted emissions testing. Automated measurement software utilized is Rohde & Schwarz EMC32, Version 8.51.0.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 6 of 21

3.3 Radiated Emissions

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A ¾" (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

For all measurements, the spectrum was scanned through all EUT azimuths and from 1 to 4 meter receive antenna height using a broadband antenna from 30MHz up to the upper frequency shown in 15.33(b)(1) depending on the highest frequency generated or used in the device or on which the device operates or tunes. For frequencies above 1GHz, linearly polarized double ridge horn antennas were used. For frequencies below 30MHz, a calibrated loop antenna was used. When exploratory measurements were necessary, they were performed at 1 meter test distance inside the semi-anechoic chamber using broadband antennas, broadband amplifiers, and spectrum analyzers to determine the frequencies and modes producing the maximum emissions. Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The test set-up was placed on top of the 0.8 meter high, 1 x 1.5 meter table. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each emission. Appropriate precaution was taken to ensure that all emissions from the EUT were maximized and investigated. The system configuration, clock speed, mode of operation or video resolution, if applicable, turntable azimuth, and receive antenna height was noted for each frequency found.

Final measurements were made in the semi-anechoic chamber using calibrated, linearly polarized broadband and horn antennas. The test setup was configured to the setup that produced the worst case emissions. The spectrum analyzer was set to investigate all frequencies required for testing to compare the highest radiated disturbances with respect to the specified limits. The turntable containing the EUT was rotated through 360 degrees and the height of the receive antenna was varied 1 to 4 meters and stopped at the azimuth and height producing the maximum emission. Each emission was maximized by varying: the mode of operation or resolution, clock or data rate, scrolling H pattern to the EUT and/or support equipment, and changing the polarity of the receive antenna, whichever produced the worst-case emissions. To record the final measurements, the analyzer detector function was set to CISPR quasi-peak mode and the bandwidth of the spectrum analyzer was set to 120kHz for frequencies below 1GHz or 1MHz for frequencies above 1GHz. For average measurements above 1GHz, the analyzer was set to peak detector with a reduced VBW setting (RBW = 1MHz, VBW = 10Hz).

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 7 of 21

4.0 ANTENNA REQUIREMENTS

Excerpt from §15.203 of the FCC Rules/Regulations:

“An intentional radiator antenna shall be designed to ensure that no antenna other than that furnished by the responsible party can be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.”

- The antennas of the Samsung Portable Handset are **permanently attached**.
- There are no provisions for connection to an external antenna.

Conclusion:

The **Samsung Portable Handset FCC ID: A3LSHVE170S** unit complies with the requirement of §15.203.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 8 of 21

5.0 SAMPLE CALCULATIONS

5.1 Conducted Emission Measurement Sample Calculation

@ 20.3 MHz

Class B limit = 60.0 dB μ V (Quasi-peak limit)
 Reading = - 57.8 dBm (calibrated quasi-peak level)
 Convert to dB μ V = - 57.8 + 107 = 49.2 dB μ V

 Margin = 49.2 - 60.0 = - 10.8 dB
 = 10.8 dB below limit

5.2 Radiated Emission Measurement Sample Calculation

@ 66.7 MHz

Class B limit = 100 μ V/m = 40.0 dB μ V/m
 Reading = - 76.0 dBm (calibrated level)
 Convert to dB μ V = - 76.0 + 107 = 31.0 dB μ V
 Antenna Factor + Cable Loss = 5.8 dB/m
 Total = 36.8 dB μ V/m

 Margin = 36.8 - 40.0 = - 3.2 dB
 = 3.2 dB below limit

Note:

$$\text{Level [dB}\mu\text{V]} = 20 \log_{10} (\text{Level } [\mu\text{V/m}])$$

$$\text{Level [dB}\mu\text{V]} = \text{Level [dBm]} + 107$$

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 9 of 21

6.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	6/7/2011	Annual	6/7/2012	N/A
-	RE2	Radiated Emissions Cable Set (VHF/UHF)	2/13/2012	Annual	2/13/2013	N/A
Agilent	E8257D	(250kHz-20GHz) Signal Generator	5/8/2011	Annual	5/8/2012	MY45470194
Agilent	8447D	Broadband Amplifier	4/17/2011	Annual	4/17/2012	2443A01900
Agilent	N9038A	MXE EMI Receiver	8/5/2011	Annual	8/5/2012	MY51210133
Agilent	N9030A	PXA Signal Analyzer	2/23/2012	Annual	2/23/2013	MY49432391
Compliance Design	Roberts	Dipole Set	5/7/2010	Biennial	5/7/2012	146
Compliance Design	Roberts	Dipole Set	5/7/2010	Biennial	5/7/2012	147
Emco	6502	Active Loop Antenna (10k - 30 MHz)	5/8/2010	Biennial	5/8/2012	267
Emco	3816/2	LISN	11/3/2010	Biennial	11/3/2012	9707-1079
Emco	3816/2	LISN	11/5/2010	Biennial	11/5/2012	9707-1077
Rohde & Schwarz	ESU26	EMI Test Receiver	4/27/2011	Annual	4/27/2012	100342
Solar Electronics	8012-50-R-24-BNC	LISN	6/23/2011	Biennial	6/23/2013	310233
Sunol	DRH-118	Horn Antenna (1-18 GHz)	6/17/2011	Biennial	6/17/2013	A042511
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	1/26/2012	Biennial	1/26/2014	A051107

Table 6-1. Annual Test Equipment Calibration Schedule

Note:

In the table above, if the equipment calibration due date falls within the test dates, care was taken to ensure that the equipment was utilized prior to the calibration due date.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset	Page 10 of 21	

7.0 ENVIRONMENTAL CONDITIONS

The temperature is controlled within range of 15°C to 35°C.

The relative humidity is controlled within range of 10% to 75%.

The atmospheric pressure is controlled within the range 86-106kPa (860-1060mbar).

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 11 of 21

8.0 TEST DATA

8.1 Summary

Company Name: Samsung Electronics, Co. Ltd.
 FCC ID: A3LSHVE170S
 Frequencies Examined: 13.56MHz

FCC Part Section(s)	RSS Section(s)	Test Description	Test Limit	Test Condition	Test Result	Reference
TRANSMITTER MODE (Tx)						
2.1049	N/A	20 dB Bandwidth	N/A	RADIATED	PASS	Section 8.2
15.225 (a)(b)(c)	RSS-210 [A2.6]	In-Band Emissions	15.848µV/m @ 30m 13.553 – 13.567 MHz 334µV/m @ 30m 13.410 – 13.553 MHz 13.567 – 13.710 MHz 106µV/m @ 30m 13.110 – 13.410 MHz 13.710 – 14.010 MHz		PASS	Section 8.4
15.225 (d) 15.209	RSS-210 [A2.6]	Out-of-Band Emissions	Emissions outside of the specified band (13.110 – 14.010 MHz) must meet the radiated limits detailed in 15.209		PASS	Section 8.5
15.225 (e)	RSS-210 [A2.6]	Frequency Stability Tolerance	± 0.01% of Operating Frequency	Temperature Chamber	PASS	Section 8.3
15.207	RSS-Gen [7.2.2]	AC Conducted Emissions 150kHz – 30MHz	< FCC 15.207 limits or < RSS-Gen table 2 limits	LINE CONDUCTED	PASS	Section 8.6
RECEIVER MODE (Rx) / DIGITAL DEVICE						
15.107	RSS-Gen [7.2.2]	AC Conducted Emissions 150kHz – 30MHz	< FCC 15.107 limits or < RSS-Gen table 2 limits	LINE CONDUCTED	PASS	Part 15B Test Report

Table 8-1. Summary of Test Results

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 12 of 21

8.2 20dB Bandwidth Measurement

§2.1049

The 20dB bandwidth is measured with a spectrum analyzer connected via a receive antenna placed near the EUT while the EUT is operating in transmission mode.

Frequency	Occupied Bandwidth
13.56MHz	24.2kHz

Table 8-2. 20dB Bandwidth Measurement

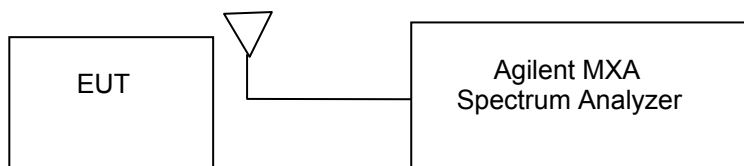


Figure 8-1. Test Instrument & Measurement Setup

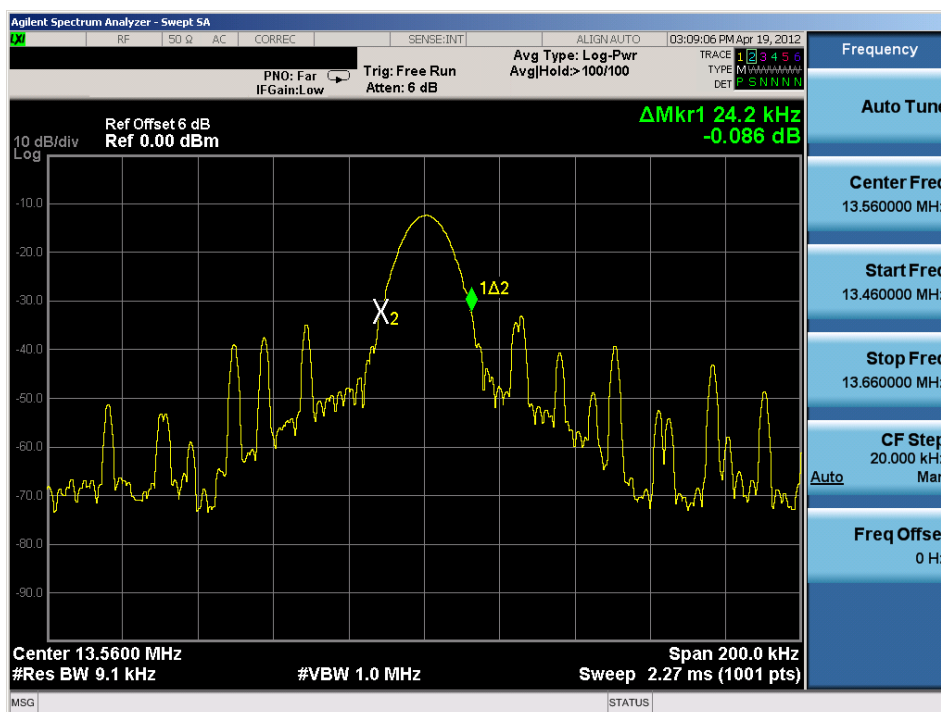


Figure 8-2. 20dB Bandwidth Plot

FCC ID: A3LSHVE170S	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 13 of 21

8.3 Frequency Stability Test Data

§15.225; RSS-210 [A2.6]

Part 15.225 requires that devices operating in the 13.553 – 13.567 MHz shall maintain the carrier frequency within 0.01% of the operating frequency over the temperature variation of -20 degrees to +50 degrees C at normal supply voltage.

OPERATING FREQUENCY: 13,560,000 Hz

REFERENCE VOLTAGE: 3.7 Vdc

DEVIATION LIMIT: ± 0.01 % = 1356Hz

VOLTAGE (%)	POWER Battery	TEMP (°C)	Frequency (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %		+ 20 (Ref)	13,559,980	-20	-0.000147
100 %		- 20	13,560,018	18	0.000133
100 %		- 10	13,560,019	19	0.000140
100 %		0	13,560,022	22	0.000162
100 %		+ 10	13,559,979	-21	-0.000155
100 %		+ 20	13,560,022	22	0.000162
100 %		+ 25	13,560,020	20	0.000147
100 %		+ 30	13,559,982	-18	-0.000133
100 %		+ 40	13,560,019	19	0.000140
100 %		+ 50	13,559,978	-22	-0.000162
Battery End Point	3.40	+ 20	13,560,023	23	0.000170
115 %	4.26	+ 20	13,560,024	24	0.000177

Table 8-3. Frequency Stability Test Data

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset	Page 14 of 21	

Frequency Stability Test Data (Cont'd)
§15.225; RSS-210 [A2.6]

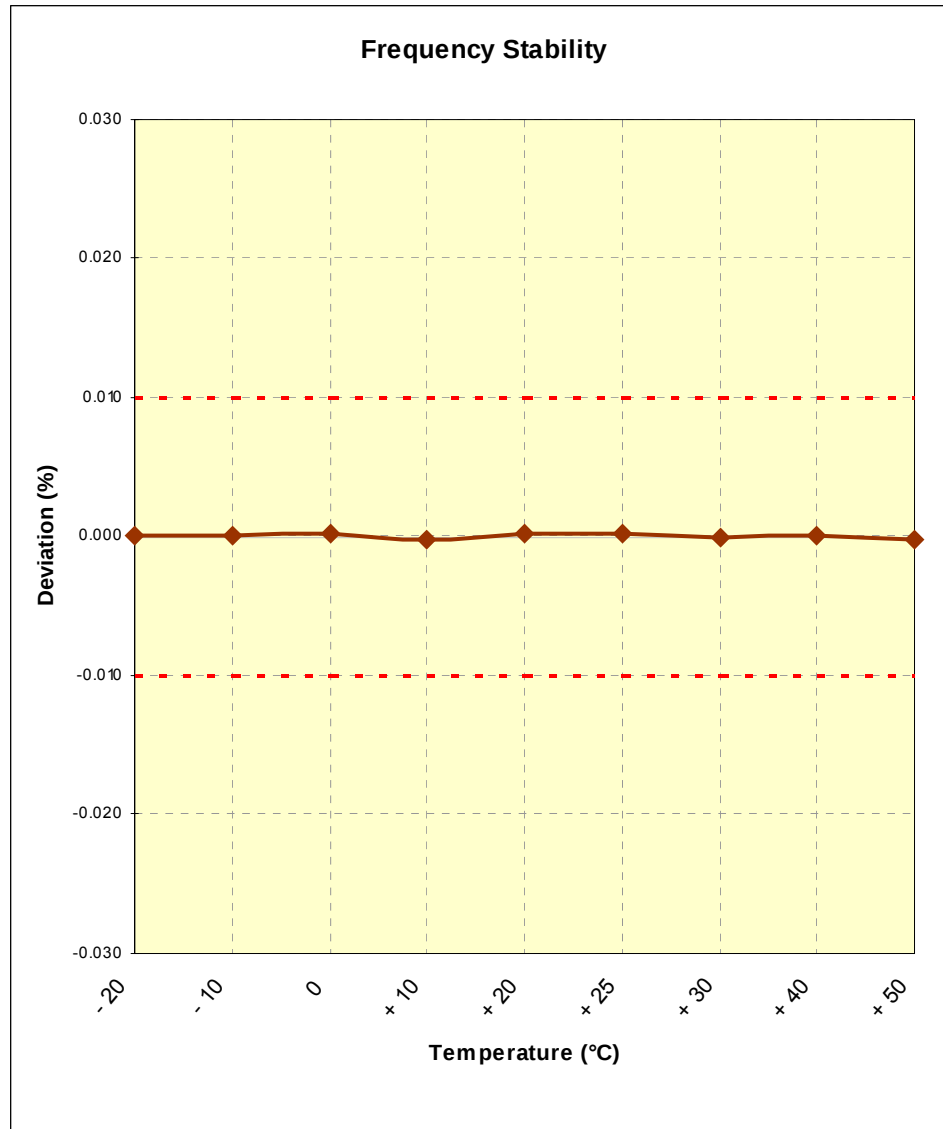


Figure 8-3. Frequency Stability Plot

FCC ID: A3LSHVE170S	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 15 of 21

8.4 In-Band Radiated Spurious Emission Measurements

§15.225(a), (b), (c); RSS-210 [A2.6]

Radiated emission testing was performed in the band 13.110 – 14.010 MHz.

Frequency: 13.56MHz

Measurement Distance: 3 Meters

Frequency [MHz]	Level [dBm]	AFCL [dB/m]	Antenna Position	Pol [H/V]	3m Field Strength [dBμV/m]	30m Field Strength [dBμV/m]	Limit [dBμV/m]	Margin [dB]
13.280	-94.58	9.99	Y	V	22.41	-17.59	40.51	-58.10
13.400	-95.13	9.98	Y	V	21.85	-18.15	40.51	-58.65
13.560	-71.18	9.97	Y	V	45.79	5.79	84.00	-78.21
13.600	-95.10	9.97	Y	V	21.87	-18.13	50.47	-68.60
13.680	-94.86	9.97	Y	V	22.11	-17.89	50.47	-68.37
13.710	-94.97	9.96	Y	V	21.99	-18.01	40.51	-58.51
13.844	-94.25	9.96	Y	V	22.71	-17.29	40.51	-57.80

Table 8-4. In-Band Radiated Measurements

NOTES:

1. All measurements were performed using a loop antenna. The antenna was positioned in three orthogonal positions (X front, Y side, Z top) and the position with the highest emission level was recorded.
2. Measurements were performed at 3m and the data was extrapolated to the specified measurement distance of 30m using the square of an inverse linear distance extrapolation factor (40 dB/decade) as specified in §15.31(f)(2). Extrapolation Factor = $20 \log_{10}(30/3)^2 = 40\text{dB}$
3. All measurements were recorded using a spectrum analyzer employing a quasi-peak detector.
4. Field Strength Level [dBμV/m] = Analyzer Level [dBm] + 107 + AFCL [dB/m]
5. AFCL [dB/m] = Antenna Factor [dB/m] + Cable Loss [dB]
6. Margin [dB] = Field Strength Level [dBμV/m] – Limit [dBμV/m]

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 16 of 21

8.5 Radiated Spurious Emission Measurements, Out-of-Band

§15.209, §15.225(d); RSS-210 [A2.6]

The EUT was tested from 9kHz up to the 1GHz excluding the band 13.110 – 14.010 MHz. All measurements up to 960MHz were recorded with a spectrum analyzer employing a quasi-peak detector. All out-of-band emissions must not exceed the limits shown in Table 8-5 per Section 15.209. A loop antenna was used to investigate emissions below 30MHz.

Frequency	Field Strength [$\mu\text{V/m}$]	Measured Distance [Meters]
0.009 – 0.490 MHz	2400/F (kHz)	300
0.490 – 1.705 MHz	24000/F (kHz)	30
1.705 – 30.00 MHz	30	30
30.00 – 88.00 MHz	100	3
88.00 – 216.0 MHz	150	3
216.0 – 960.0 MHz	200	3
Above 960.0 MHz	500	3

Table 8-5. Radiated Limits – Out of band

Sample Calculation

- o Field Strength Level [$\text{dB}\mu\text{V/m}$] = Analyzer Level [dBm] + 107 + AFCL [dB/m]
- o AFCL [dB/m] = Antenna Factor [dB/m] + Cable Loss [dB]
- o Margin [dB] = Field Strength Level [$\text{dB}\mu\text{V/m}$] – Limit [$\text{dB}\mu\text{V/m}$]

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 17 of 21

Radiated Spurious Emission Measurements, Out-of-Band (Cont'd)

§15.209, §15.225(d); RSS-210 [A2.6]

Tx Frequency 13.56MHz

Measurement Distance: 3 Meters

Frequency [MHz]	Level [dBm]	AFCL [dB/m]	Pol [H/V]	3m Field Strength [dBμV/m]	Limit [dBμV/m]	Margin [dB]
27.12	-95.21	7.96	V	19.75	69.54	-49.79
40.68	-109.89	11.78	V	8.88	40.00	-31.12
54.24	-111.33	11.92	V	7.59	40.00	-32.41
67.80	-111.33	10.22	V	5.89	40.00	-34.11
81.36	-108.97	7.15	V	5.18	40.00	-34.82
149.16	-99.56	16.30	V	23.75	43.52	-19.77
155.18	-101.10	17.40	V	23.30	43.52	-20.23

Table 8-6. Radiated Measurements

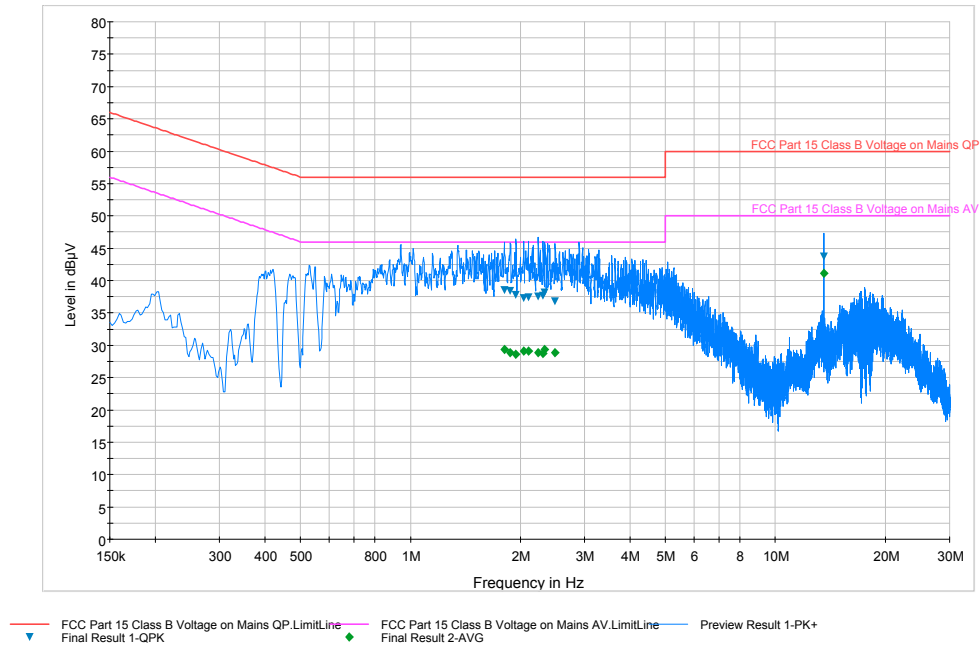
NOTES:

1. All measurements were recorded using a spectrum analyzer employing a quasi-peak detector for emissions below 960MHz.
2. Both Vertical and Horizontal polarities of the receive antenna were evaluated with the worst case emissions being reported. Below 30MHz the loop antenna was positioned in 3 orthogonal planes (X front, Y side, Z top) to determine the orientation resulting in the worst case emissions.
3. The EUT is supplied with nominal AC voltage and/or a new/fully-recharged battery.
4. The spectrum is measured from 9kHz to the 10th harmonic and the worst-case emissions are reported.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 18 of 21

8.6 Line Conducted Measurement Data

§15.207; RSS-Gen (7.2.2)



Plot 8-1. Line-Conducted Test Plot (L1)

Frequency (MHz)	Line	Quasipeak (dBµV)	Corr. (dB)	Limit (dBµV)	Margin (dB)	Average (dBµV)	Corr. (dB)	Limit (dBµV)	Margin (dB)
1.81	L1	38.5	0.2	56	17.5	29.4	0.2	46	16.6
1.88	L1	38.4	0.2	56	17.6	28.9	0.2	46	17.1
1.95	L1	37.7	0.2	56	18.3	28.6	0.2	46	17.4
2.04	L1	37.3	0.2	56	18.7	29.1	0.2	46	16.9
2.10	L1	37.3	0.2	56	18.7	29.1	0.2	46	16.9
2.24	L1	37.5	0.2	56	18.5	28.8	0.2	46	17.2
2.31	L1	37.7	0.2	56	18.3	28.7	0.2	46	17.3
2.33	L1	38.2	0.2	56	17.8	29.3	0.2	46	16.7
2.49	L1	36.7	0.2	56	19.3	28.8	0.2	46	17.2
13.56	L1	43.7	0.5	60	16.3	41.1	0.5	50	8.9

Table 8-7. Line-Conducted Test Data (L1)

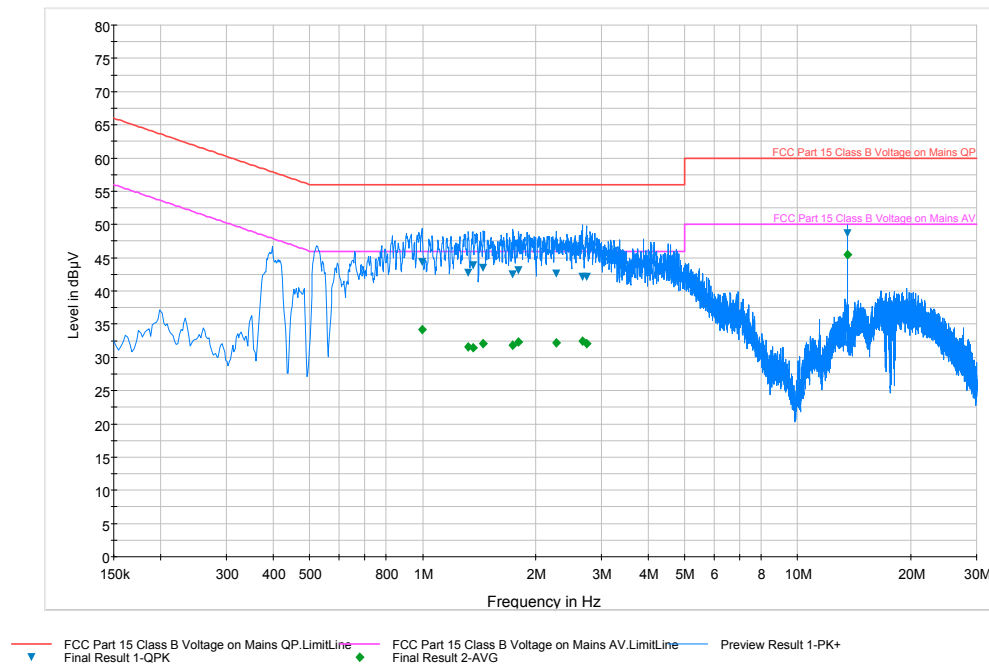
Notes:

- All Modes of operation were investigated and the worst-case emissions are reported.
- The limit for Class B device(s) from 150kHz to 30MHz are specified in Section 15.207 of the Title 47 CFR.
- Corr. (dB) = Cable loss (dB) + LISN insertion factor (dB)
- QP/AV Level (dBµV) = QP/AV Analyzer/Receiver Level (dBµV) + Corr. (dB)
- Margin (dB) = QP/AV Limit (dBµV) - QP/AV Level (dBµV)
- Traces shown in plot are made using a peak detector.
- Deviations to the Specifications: None.

FCC ID: A3LSHVE170S	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 19 of 21

Line Conducted Measurement Data (Cont'd)

§15.207; RSS-Gen (7.2.2)



Plot 8-2. Line-Conducted Test Plot (N)

Frequency (MHz)	Line	Quasipeak (dBµV)	Corr. (dB)	Limit (dBµV)	Margin (dB)	Average (dBµV)	Corr. (dB)	Limit (dBµV)	Margin (dB)
1.00	N	44.4	0.2	56	11.6	34.2	0.2	46	11.8
1.32	N	42.7	0.2	56	13.3	31.6	0.2	46	14.4
1.36	N	43.8	0.2	56	12.2	31.4	0.2	46	14.6
1.45	N	43.4	0.2	56	12.6	32.1	0.2	46	13.9
1.74	N	42.5	0.2	56	13.5	31.8	0.2	46	14.2
1.80	N	43.1	0.2	56	12.9	32.3	0.2	46	13.7
2.27	N	42.6	0.2	56	13.4	32.2	0.2	46	13.8
2.67	N	42.1	0.2	56	13.9	32.5	0.2	46	13.5
2.73	N	42.1	0.2	56	13.9	32.1	0.2	46	13.9
13.56	N	48.7	0.5	60	11.3	45.4	0.5	50	4.6

Table 8-8. Line-Conducted Test Data (N)

Notes:

- All Modes of operation were investigated and the worst-case emissions are reported.
- The limit for Class B device(s) from 150kHz to 30MHz are specified in Section 15.207 of the Title 47 CFR.
- Corr. (dB) = Cable loss (dB) + LISN insertion factor (dB)
- QP/AV Level (dBµV) = QP/AV Analyzer/Receiver Level (dBµV) + Corr. (dB)
- Margin (dB) = QP/AV Limit (dBµV) - QP/AV Level (dBµV)
- Traces shown in plot are made using a peak detector.
- Deviations to the Specifications: None.

FCC ID: A3LSHVE170S	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 20 of 21

9.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSHVE170S** has been tested to show compliance with the requirements specified in §15.225 of the FCC Rules and RSS-210 of the Industry Canada rules.

FCC ID: A3LSHVE170S		FCC Pt. 15.225 MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1204030418.A3L	Test Date(s): April 20, 2012	EUT Type: Portable Handset		Page 21 of 21